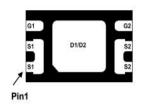
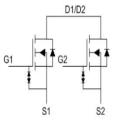


## **Main Product Characteristics:**

V <sub>DSS</sub>	20V		
R <sub>DS</sub> (on)	6.6mΩ (typ.)		
I <sub>D</sub>	11A		







DFN2\*3-6L

Marking and Pin
Assignments

**Schematic Diagram** 

### **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



## **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

# **Absolute Max Rating:**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ①	11	^
I <sub>DM</sub>	Pulsed Drain Current ②	70	Α
P <sub>D</sub> @TC = 25°C	Power Dissipation ③	1.56	
V <sub>DS</sub>	Drain-Source Voltage	20	V
V <sub>GS</sub>	Gate-to-Source Voltage	12	V
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C



# **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
Reja	Junction-to-ambient (t $\leq$ 10s) $\oplus$	_	80	°C/W

## **Electrical Characterizes** @T<sub>A</sub>=25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	20	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
		_	6.6	7.2	mΩ	V <sub>GS</sub> =4.5V,I <sub>D</sub> =5.5A
		_	7	7.5		V <sub>GS</sub> =4V,I <sub>D</sub> =5.5A
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source on-resistance	_	7.1	8.2		V <sub>GS</sub> =3.7V,I <sub>D</sub> =5.5A
		_	7.6	9		V <sub>GS</sub> =3.1V,I <sub>D</sub> =5.5A
		_	8.7	10.2		V <sub>GS</sub> =2.5V,I <sub>D</sub> =5.5A
V <sub>GS(th)</sub>	Gate threshold voltage	0.5	_	1.5	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	1	μA	V <sub>DS</sub> =18V,V <sub>GS</sub> = 0V
	Gate-to-Source forward leakage	_	_	10	μА	V <sub>GS</sub> =8V
I <sub>GSS</sub>		_	_	-10		V <sub>GS</sub> = -8V
Qg	Total gate charge	_	23	_		I <sub>D</sub> = 11A,
Q <sub>gs</sub>	Gate-to-Source charge	_	4	_	nC	V <sub>DS</sub> =16V,
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	_	8	_		V <sub>GS</sub> = 4.5V
t <sub>d(on)</sub>	Turn-on delay time	_	10	_		$V_{GS}$ =4.5V, $V_{DS}$ =16V, $R_{GEN}$ =6 $\Omega$
tr	Rise time	_	41	_		
t <sub>d(off)</sub>	Turn-Off delay time	_	65	_	ns	
t <sub>f</sub>	Fall time	_	30	_		I <sub>D</sub> = 5.5A
C <sub>iss</sub>	Input capacitance	_	1765	_		V <sub>GS</sub> = 0V
Coss	Output capacitance	_	182	_	pF	V <sub>DS</sub> = 10V
C <sub>rss</sub>	Reverse transfer capacitance	_	155	_		f = 1MHz

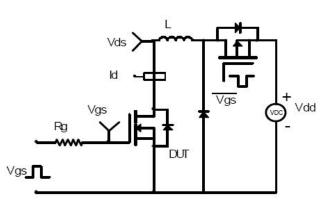
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
L	Continuous Source Current		_ 11	44		MOSFET symbol	
ls ls	(Body Diode)	_		A	showing the		
	Pulsed Source Current	70			70		integral reverse
Ism	(Body Diode)		70 A	p-n junction diode.			
V <sub>SD</sub>	Diode Forward Voltage	_	_	1	V	I <sub>S</sub> =1A, V <sub>GS</sub> =0V	

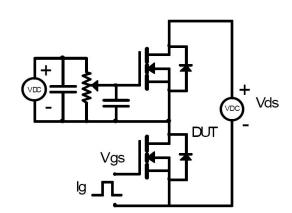


## **Test Circuits and Waveforms**

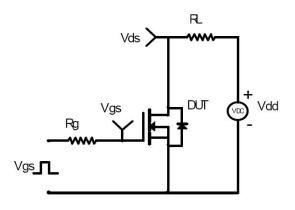
#### **EAS Test Circuit:**



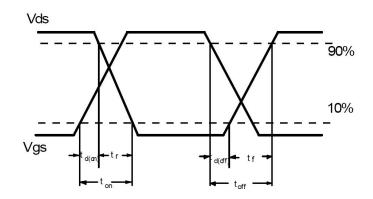
#### **Gate Charge Test Circuit:**



#### **Switching Time Test Circuit:**



#### **Switching Waveforms:**

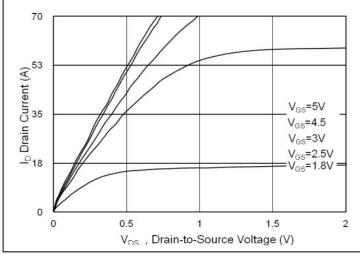


#### Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of  $R_{\texttt{9JA}}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



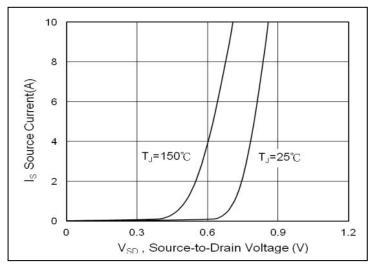
# **Typical Electrical and Thermal Characteristics**



21 17 (GE) 13 9 1.5 2.2 2.9 3.6 4.3 5 V<sub>GS</sub> (V)

Figure 1. Typical Output Characteristics

Figure 2. Rdson vs. Gate-Source Voltage



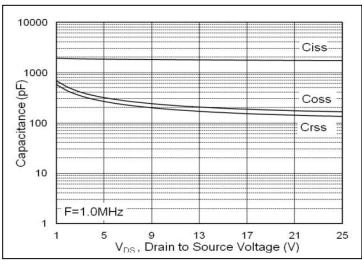
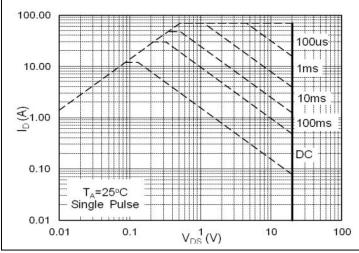


Figure 3. Forward Characteristics of Reverse

Figure 4. Rdson vs. Drain Current



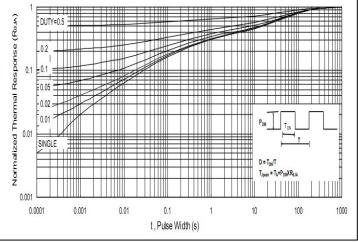
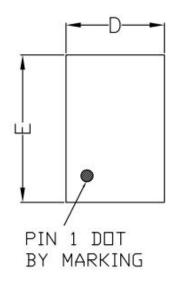


Figure 5. Safe Operating Area

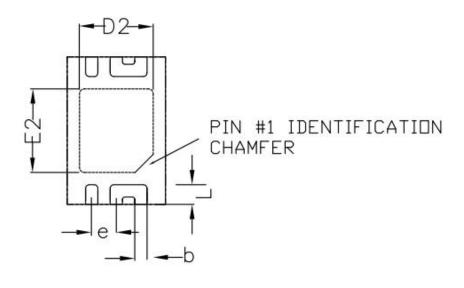
Figure 6. Transient Thermal Impedance



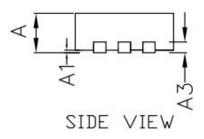
## **Mechanical Data:**







BOTTOM VIEW



	COMMON DIME	(MM)2NDI2N				
PKG.	W:VERY VERY THIN					
REF.	MIN.	N□M.	MAX			
Α	0.70	0.75	0.80			
A1	0.00	8.7	0.05			
A3	0.195	0.203	0.211			
D	1.95	2.00	2.05			
E	2.95	3.00	3.05			
b	0.20	0.25	0.30			
L	0.35	0.40	0.45			
D2	1.45	1.50	1.55			
E2	1.65	1.70	1.75			
е	0.50 BSC					





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